

Meeting Report on the 7th International Conference on Inelastic X-ray Scattering (IXS2010)

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The 7th International Conference on Inelastic X-ray Scattering (IXS2010) was hosted jointly by the European Synchrotron Radiation Facility (ESRF) and the Politecnico di Milano, and was held from 11 to 14 October in the WTC conference center in Grenoble. The IXS conference series was founded in 1993 and is held approximately every three years. It is the prime venue for scientists working in the field of inelastic x-ray scattering (IXS), and provides a forum for the presentation of novel results, discussion on present and future trends and for an intense exchange between participants utilising the various IXS techniques for a wide variety of different applications. The conference covered the techniques of electronic resonant and non-resonant scattering (in the soft- and hard x-ray regime), emission spectroscopy, meV-resolved atomic dynamics, nuclear inelastic scattering, Compton scattering, and thermal diffuse scattering.

The conference started with a visit to the ESRF and a welcome reception on Sunday, 10 October. The scientific program started on Monday with two Overview talks and a Plenary talk on correlated electron systems in the light of X-rays and neutrons. The conference sessions were organised in ten themes, featuring Correlated electron systems, 3D Transition Metal Compounds, Magnetism, Superconductivity & Related Phenomena, Elements & Advanced Materials, Chemistry & Biology, Liquids, Glasses, and Gas Phase studies, Earth and Planetary Science, and New Scientific Frontiers. In total there were 3 plenary talks, 29 invited talks and 16 oral contributions. Two poster sessions were scheduled on Tuesday and Wednesday in the late afternoon where 84 posters were exposed and lively discussed. The conference concluded with a visit to Vienne and the vineyards of the Côte Rotie on Friday.

IXS2010 attracted 162 participants from 61 different institutions from Europe (115 - from France: 49), America (23 - USA: 22, Canada: 1) and Asia (24 - Japan: 15, Taiwan: 5, India: 2, China: 1, Korea: 1). 33 participants were students.

The conference was partly funded through registration fees. Financial supports were received from the International Union of Crystallography (IUCr), the ESRF, the City of Grenoble, and Grenoble – Alpes Métropole. Sponsors include Huber Diffraktionstechnik GmbH & Co. KG and KOHZU Precision Co Ltd. These exhibited as well their products along with representatives from SESO (Aix-en-Provence, France) and the XRS Tech Company (New Jersey, USA).

IXS2010 financially supported 24 young scientists, mainly from abroad. The IUCr supported IXS2010 with 3000 USD, and the funds were used to partially support the travel and accommodation expenses of six young scientists.

The decision on the host and location of the next conference, to be held in 2013, shall be taken in the first half of 2011.